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Pre-Conditioning	Via machining	Via filling	Screen printing		
Cutting & Firing	Laminating	Stacking			







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	Mechanical drill and punches	Laser machining	
	Low capital cost	High capital cost	
	Single use	Multipurpose	
	Low punching rate	High punching rate	
	Clean and precise diameter	Not very clean, precision suffers	
	Holes only	Arbitrary shape possible	
	No optimization required	Hard to optimize	
	Direct contact with the material	No direct contact with material	
	Short tool life	Long life	
			Slide 24



























153-	11. A.					
Loss Comparison with Various SIW Technologies						
Frequency (GHz)	Insertion loss (dB/mm)	Conductor loss scaling to 300 GHz (dB/mm)				
50	0.03	0.07				
60	0.20	0.45				
74	0.70	1.41				
79	0.17	0.33				
83	1.2	2.3				
100	0.01	0.017				
105	8.98	15.18				
400	0.086	0.074				
300	3.88	3.88				
		Imperial College				
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